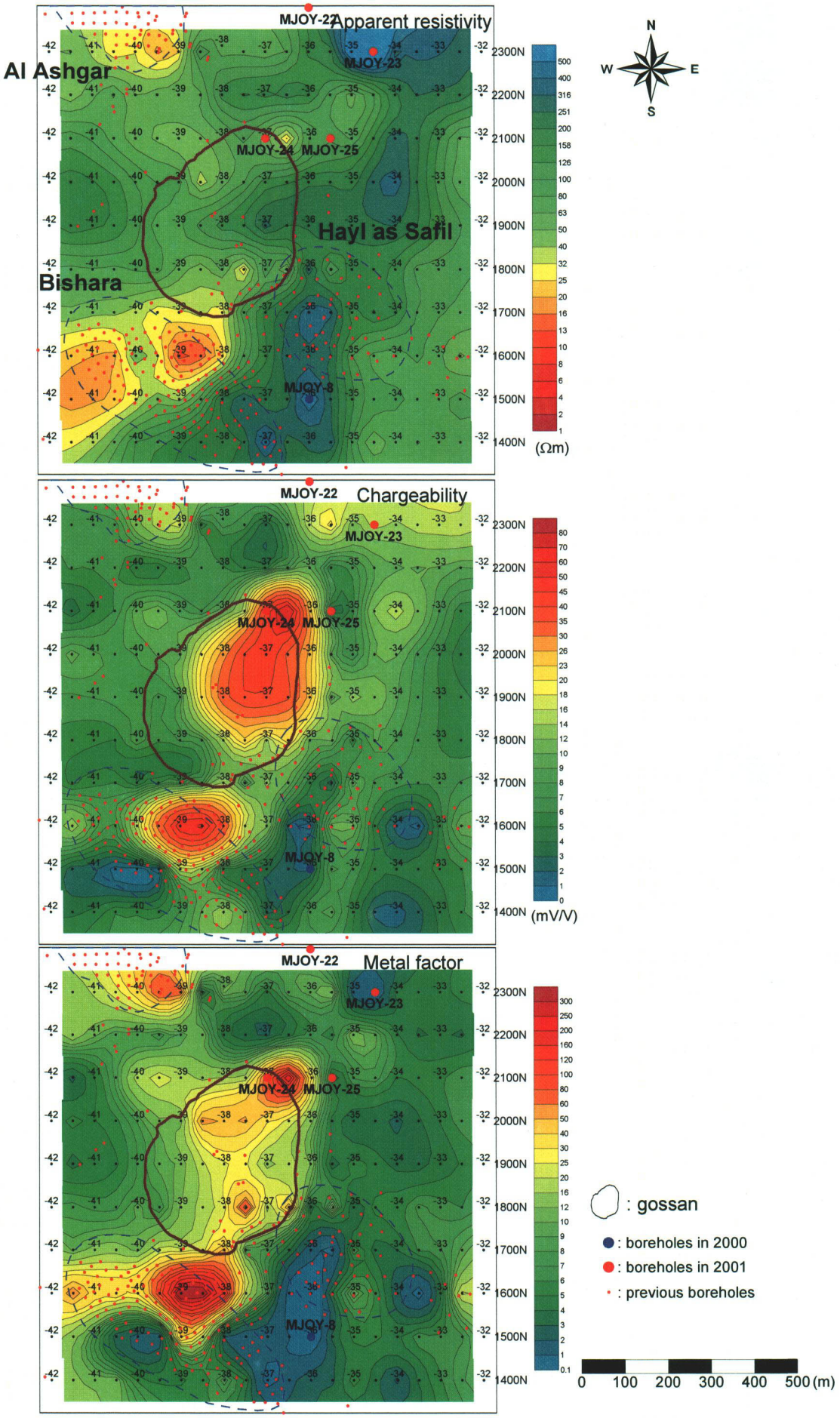


Fig. II -2-35(1) 2D analysis plane maps at the depth of 50m in Hayl as Safil area

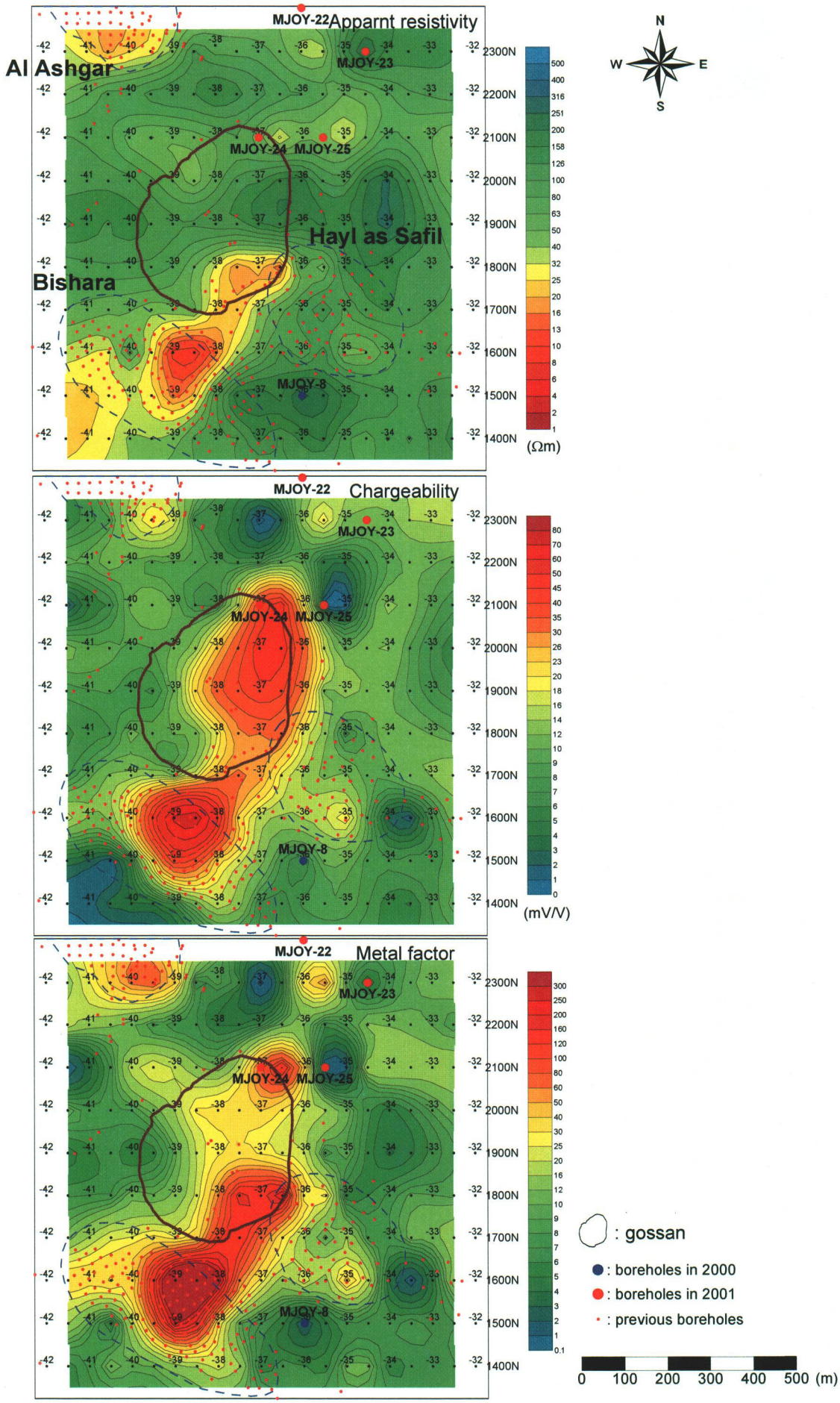


Fig. II -2-35(2) 2D analysis plane maps at the depth of 75m in Hayl as Safil area

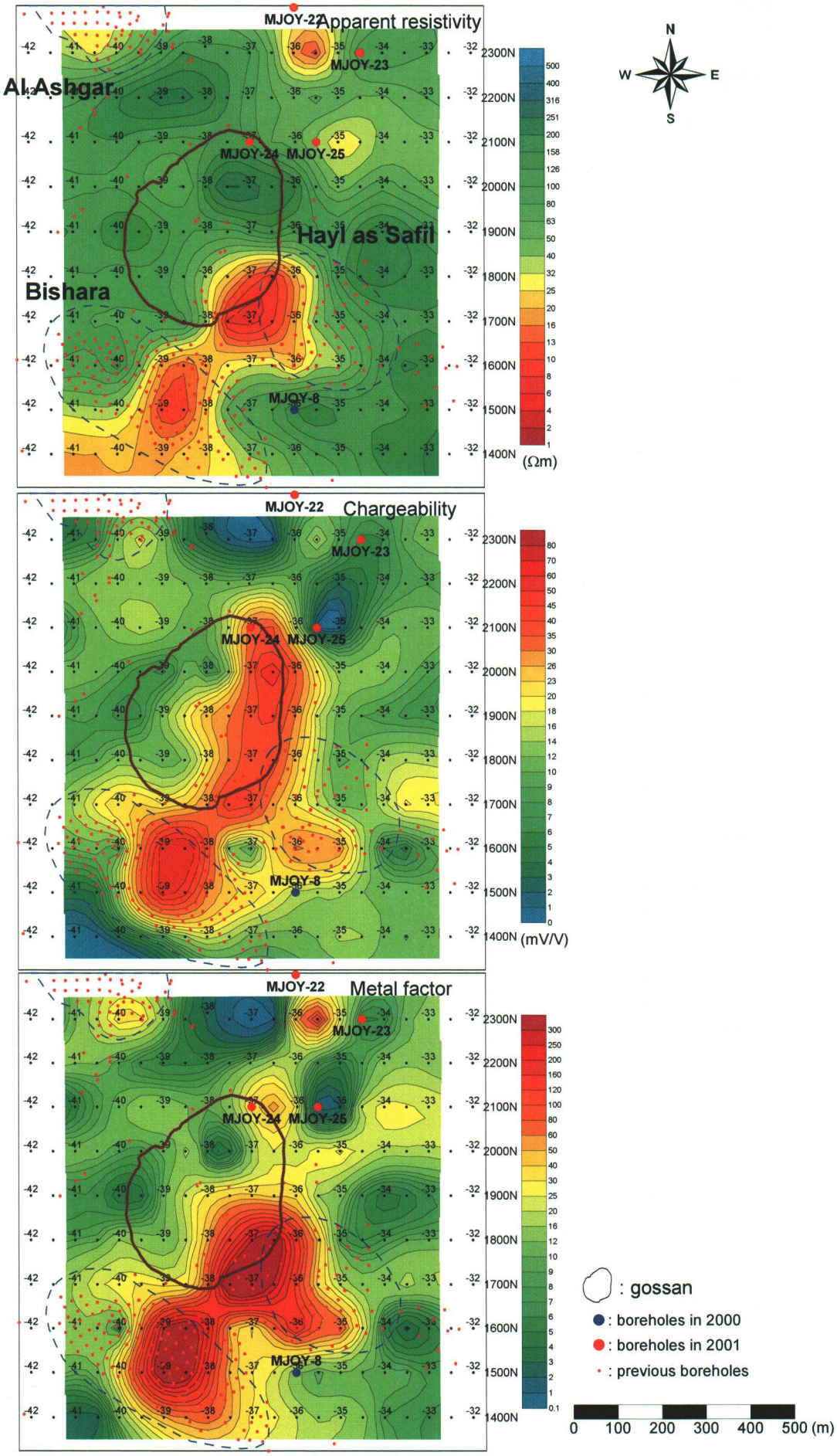


Fig. II-2-35(3) 2D analysis plane maps at the depth of 100m in Hayl as Safil area

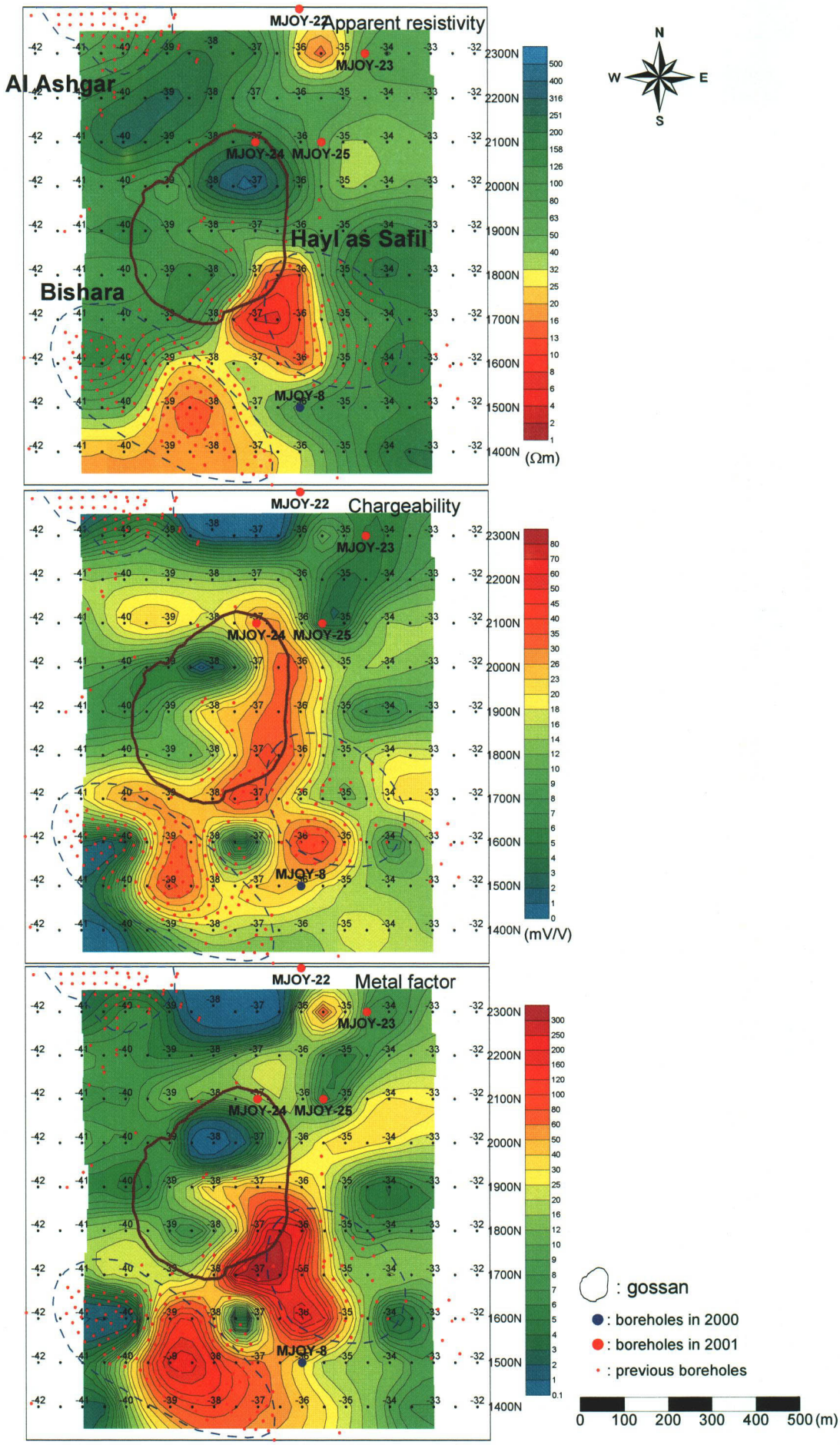


Fig. II -2-35(4) 2D analysis plane maps at the depth of 125m in Hayl as Safil area

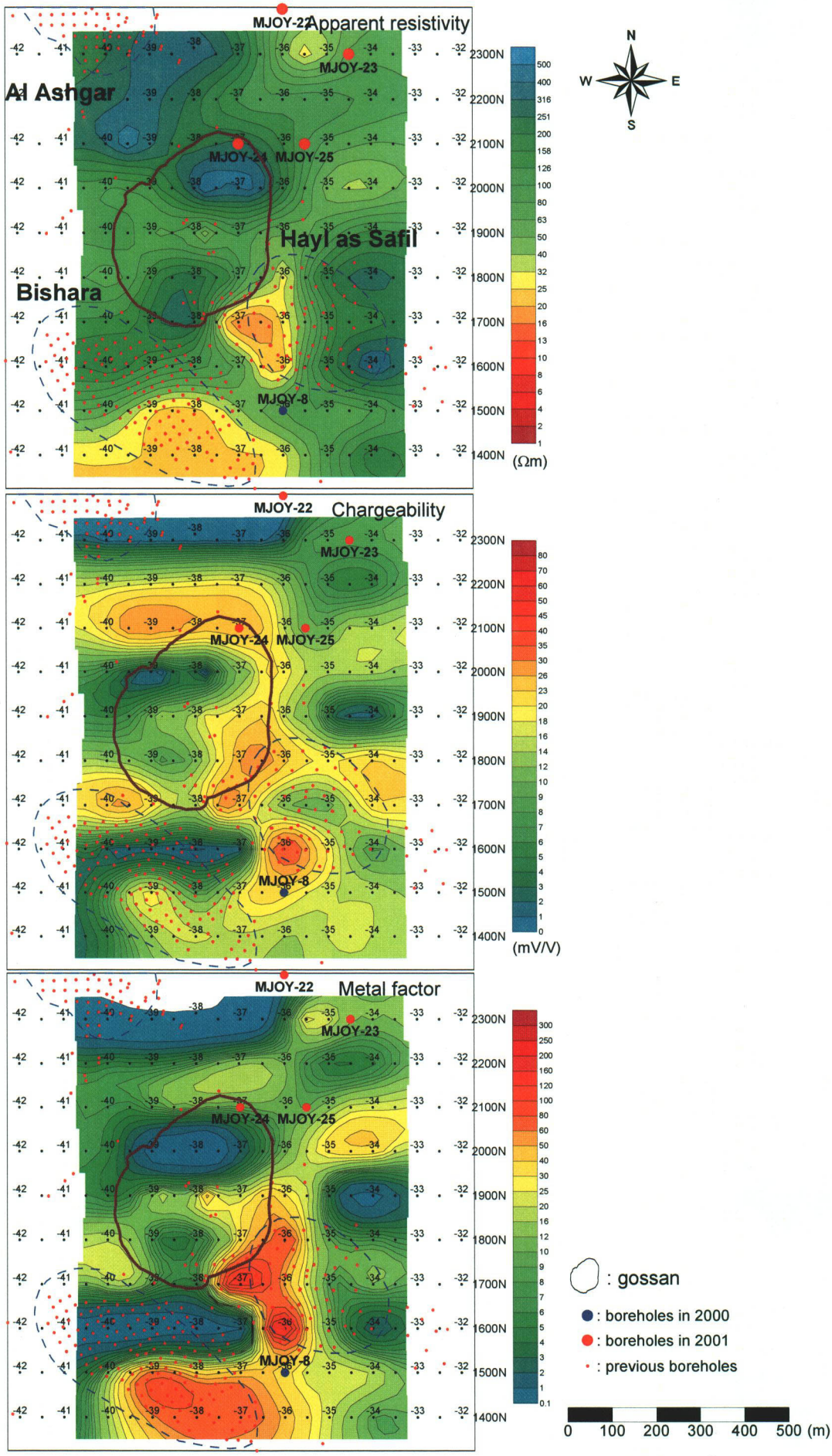


Fig. II -2-35(5) 2D analysis plane maps at the depth of 150m in Hayl as Safil area

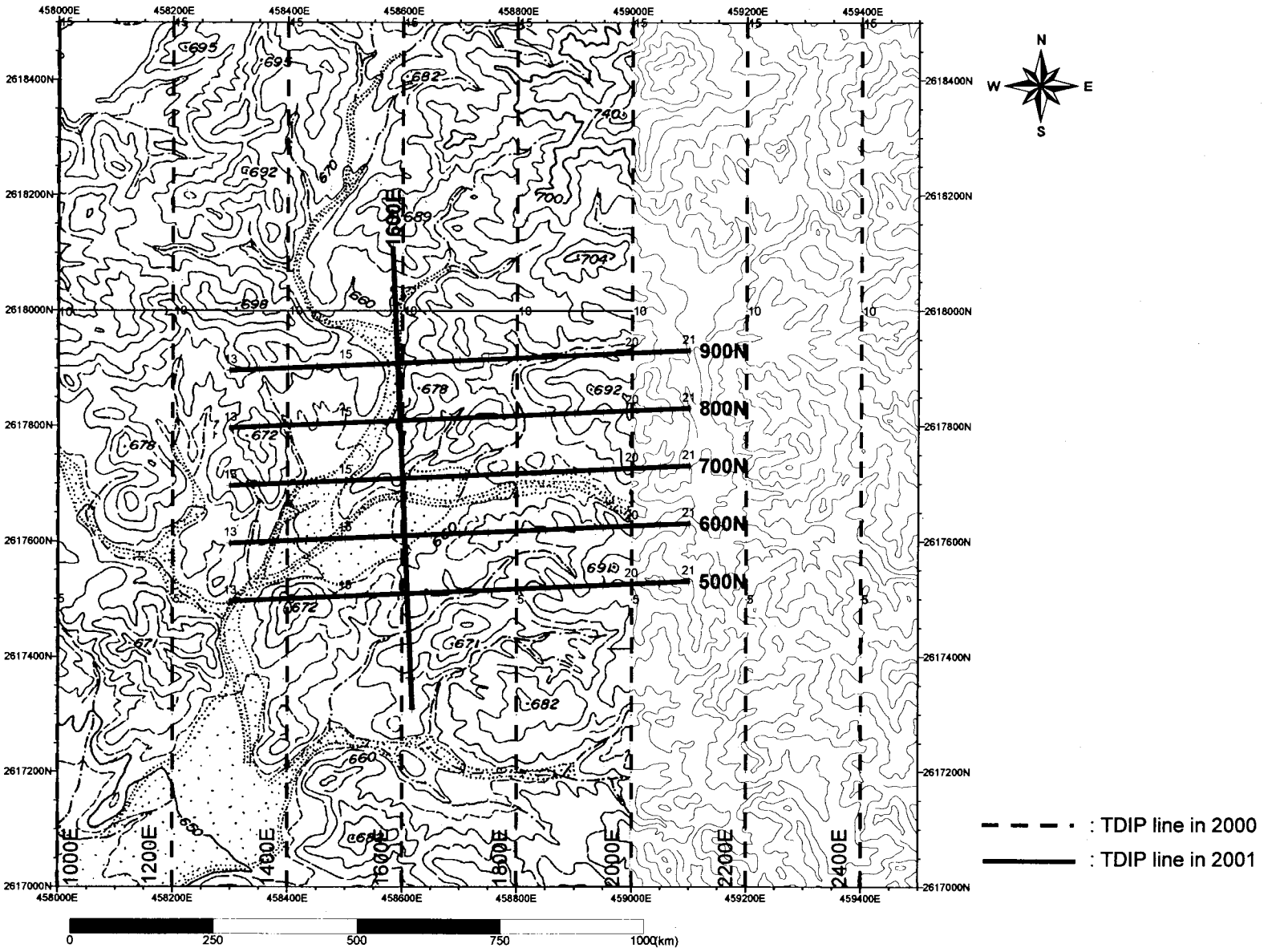


Fig. II-2-36 Geophysical survey location in Najaid area

pseudo-sections and plane maps are indicated in Figs. II-2-37 (1)~(4) and Figs. II-2-38 (1)~(3), respectively. 2-D analysis for sections and plane maps are illustrated in Figs. II-2-39 (1)~(4) and Figs. II-2-40 (1)~(3), respectively.

The apparent resistivity values detected in this area ranged from 52.5Ωm to 687Ωm with an average value of 257Ωm. Chargeability was detected in the range from 1.8 to 27.2mV/V with an average of 13.6mV/V.

In this area, apparent resistivity shows entirely high values and therefore any single low resistivity cannot be seen in the entire area. In relation to chargeability, high chargeability values are seen near the central part of the survey area in 2 places. One of them was detected in Line 600N around the station 18 at shallow levels (N=1) and extended its distribution depths towards the central part. The other one can be seen around the lines 800N and 700N between the points 15.5 and 16.0 at deep levels (N=3~4) with a distribution pattern along NS direction. 2-D analysis shows almost same distribution pattern.

2-5-6 Electrical measurements of rock samples

In Phase I, 42 representative rock samples from the survey area were analyzed, while 21 samples were analyzed in Phase II.

In general, resistivity and IP measurements in rocks may not reflect in a direct way the intrinsic resistivity or chargeability because of different degree of alteration and water content over the survey area, however clear ideas can be obtained related to the relative variations between rocks units and mineralization.

(1) Measurement method

Measurement of the electrical properties of rock samples, such as resistivity and IP chargeability were carried out on some samples selected from the survey area. The rock samples were formed into a cylindrical shape and thereafter, soaked into water for a reasonable amount of days but not less than 48 hours. Apparent resistivities as well as chargeability values were measured according to the IP time domain procedures in the laboratory. For this purpose, it was used a Lab Downhole Transmitter LDT-10 made by Zonge. During the determinations of the resistivity and chargeability values, the following formulas were utilized:

For Resistivity:

$$\rho = \frac{A}{L} \times \frac{V_p}{I},$$

where ρ is resistivity (Ωm), A the section of the sample (m^2), L the length of the rock sample (m), V_p the voltage (V) and I the current (A)

For Chargeability:

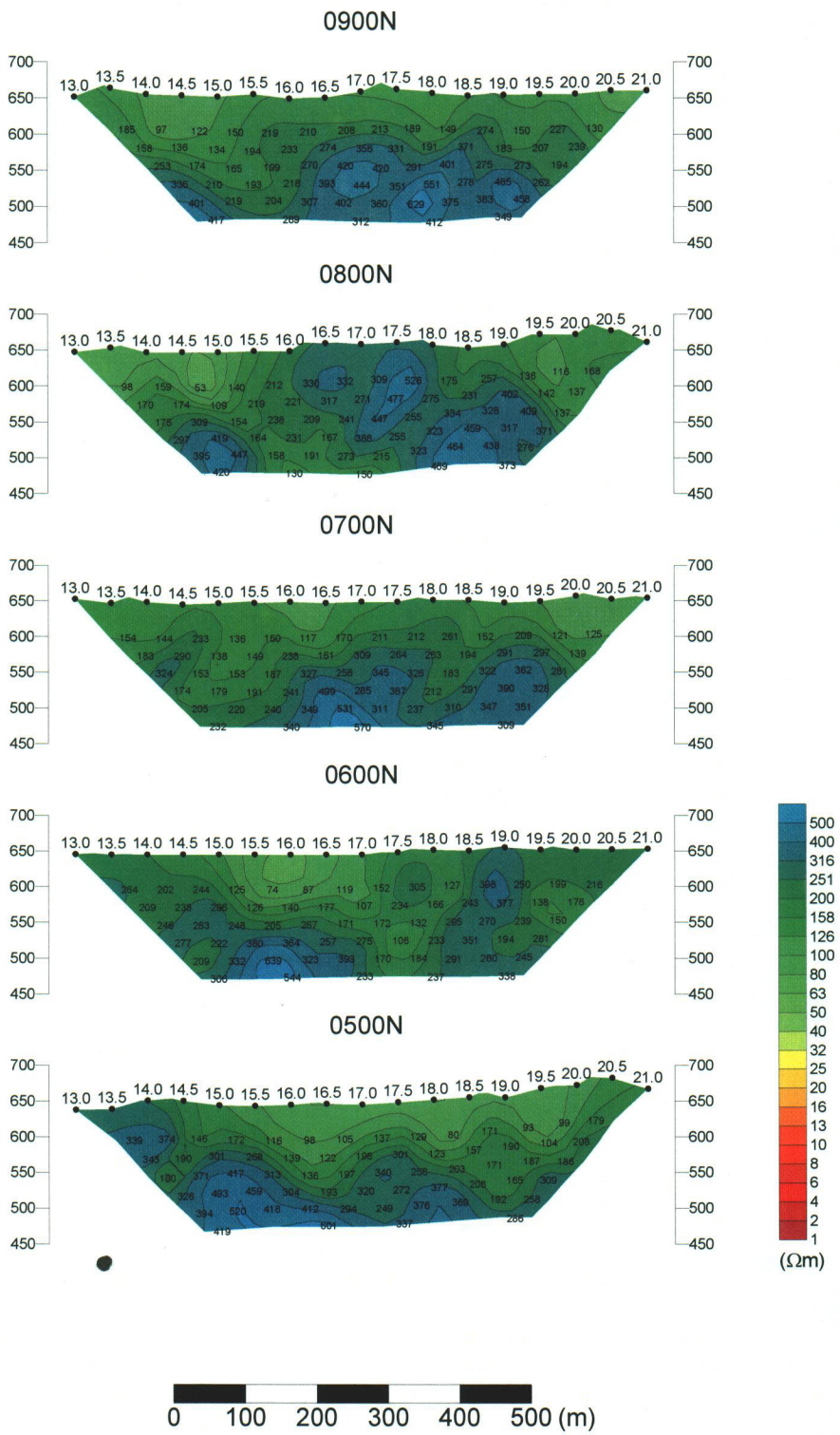


Fig. II -2-37(1) Apparent resistivity pseudo-sections of E-W lines in Najaid area

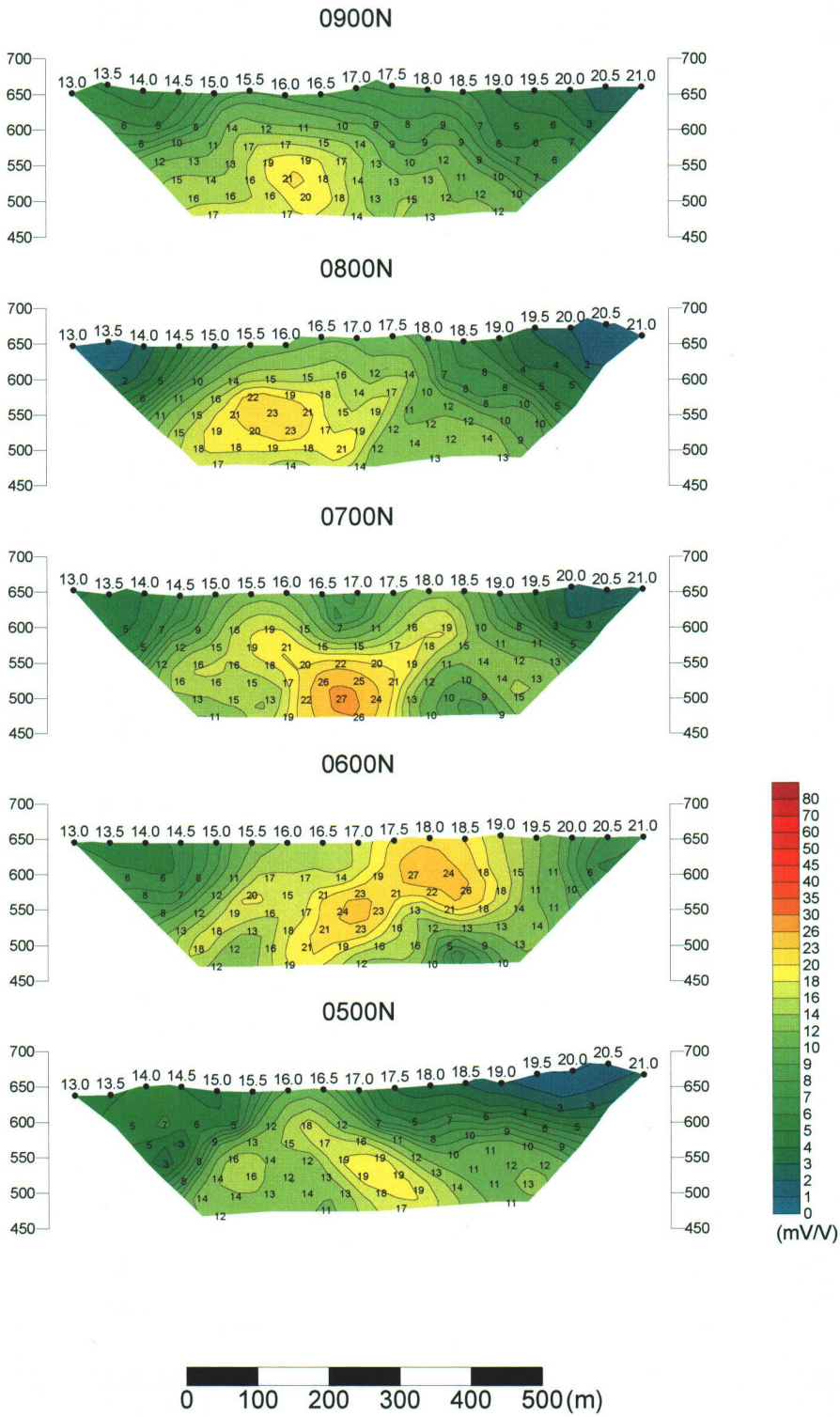


Fig. Ⅱ-2-37(2) Chargeability pseudo-sections of E-W lines in Najaid area

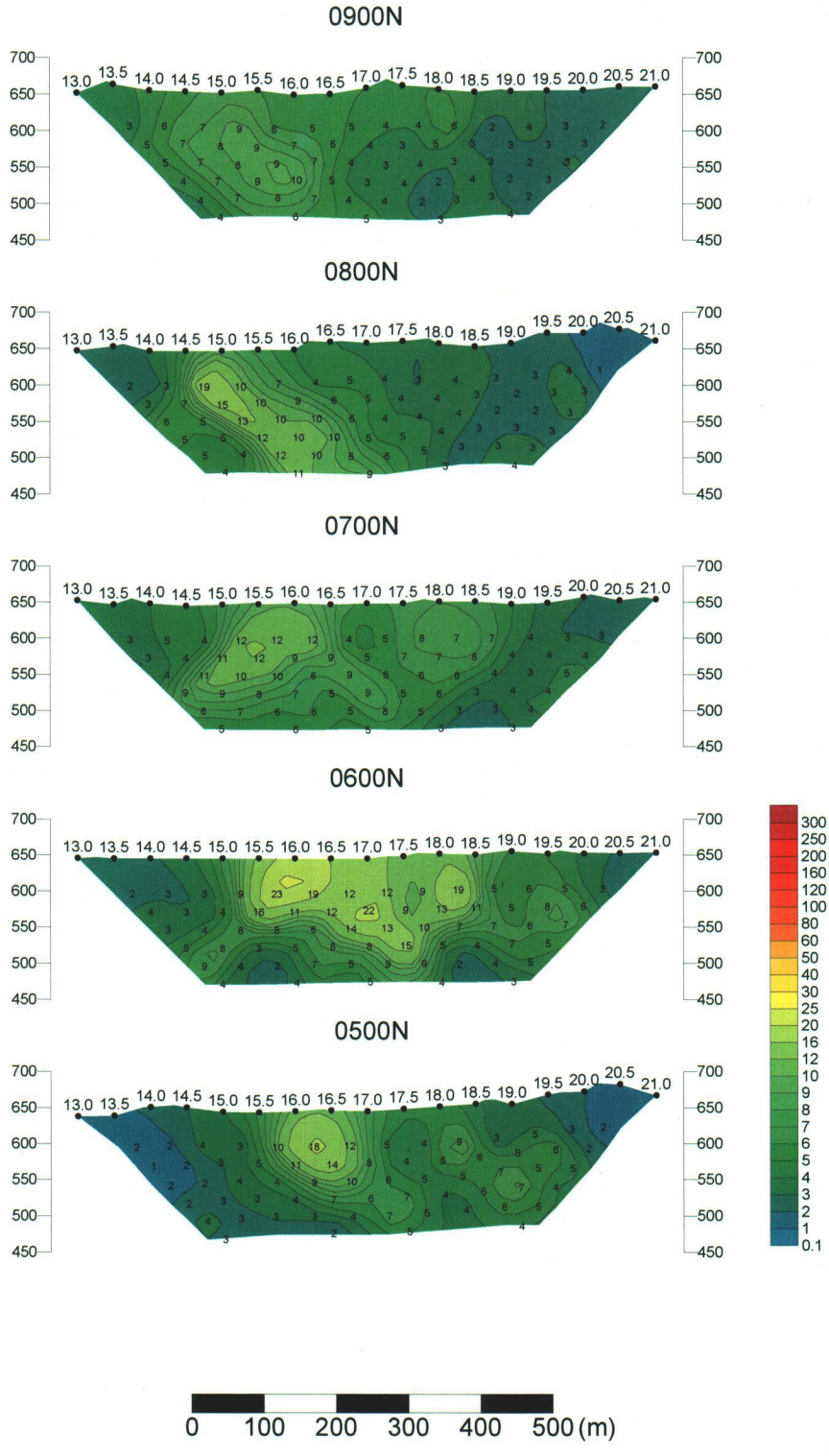


Fig. II -2-37(3) Metal factor pseudo-sections of E-W lines in Najaid area

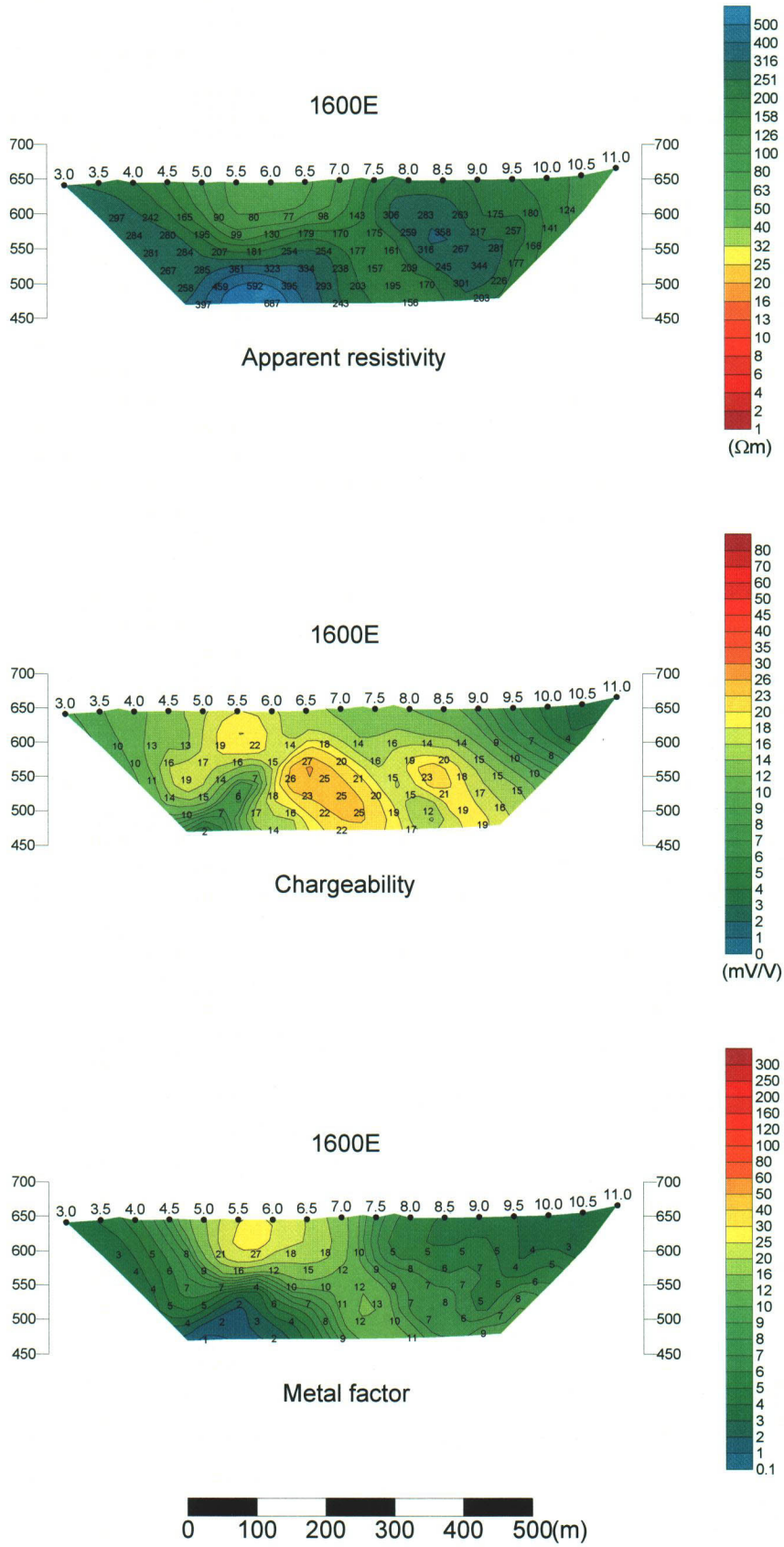


Fig. II -2-37(4) TDIP pseudo-sections of N-S lines in Najaid area

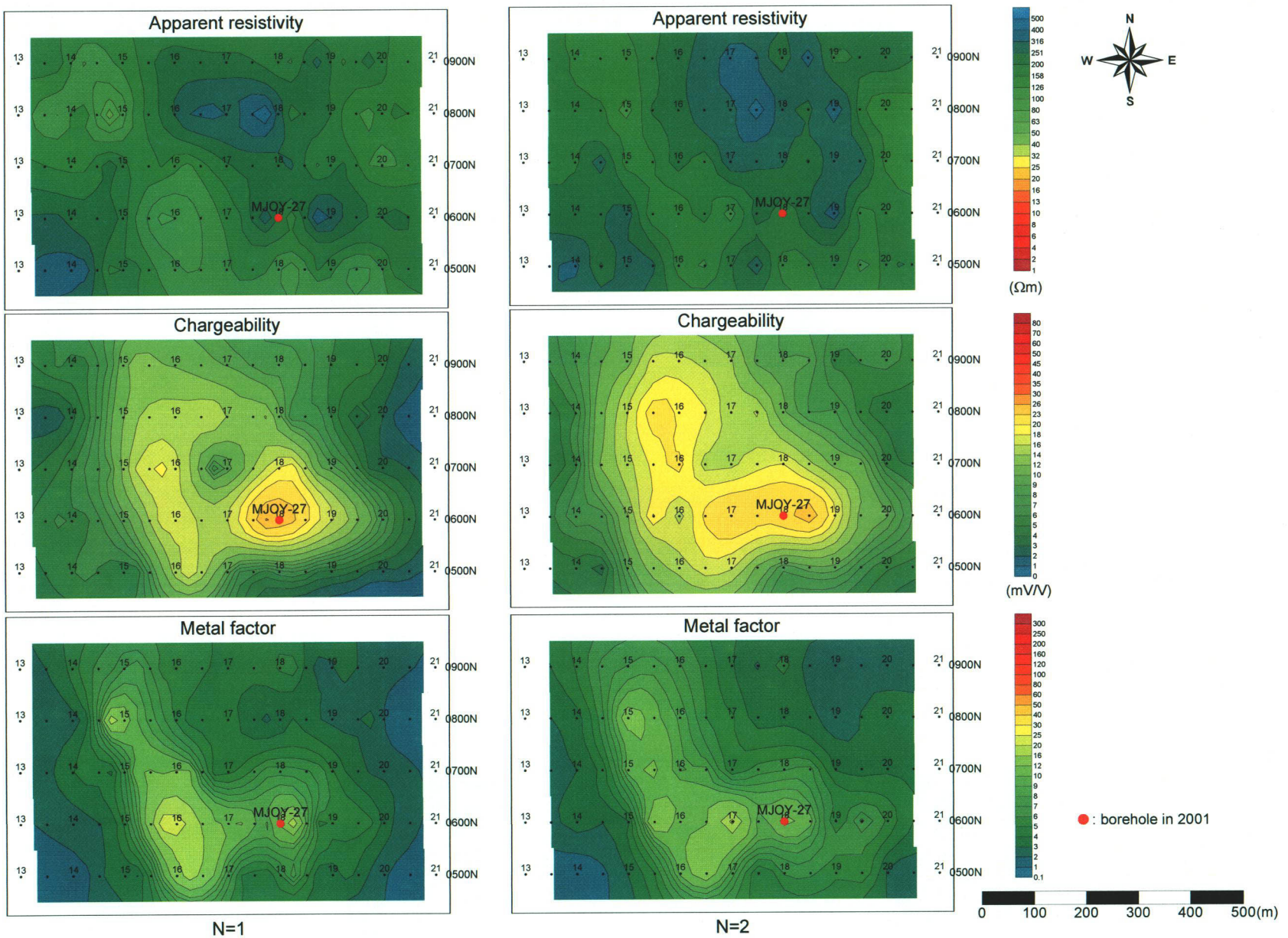


Fig. Ⅱ 2-38(1) TDIP plane maps for N=1 and 2 in Najaid area

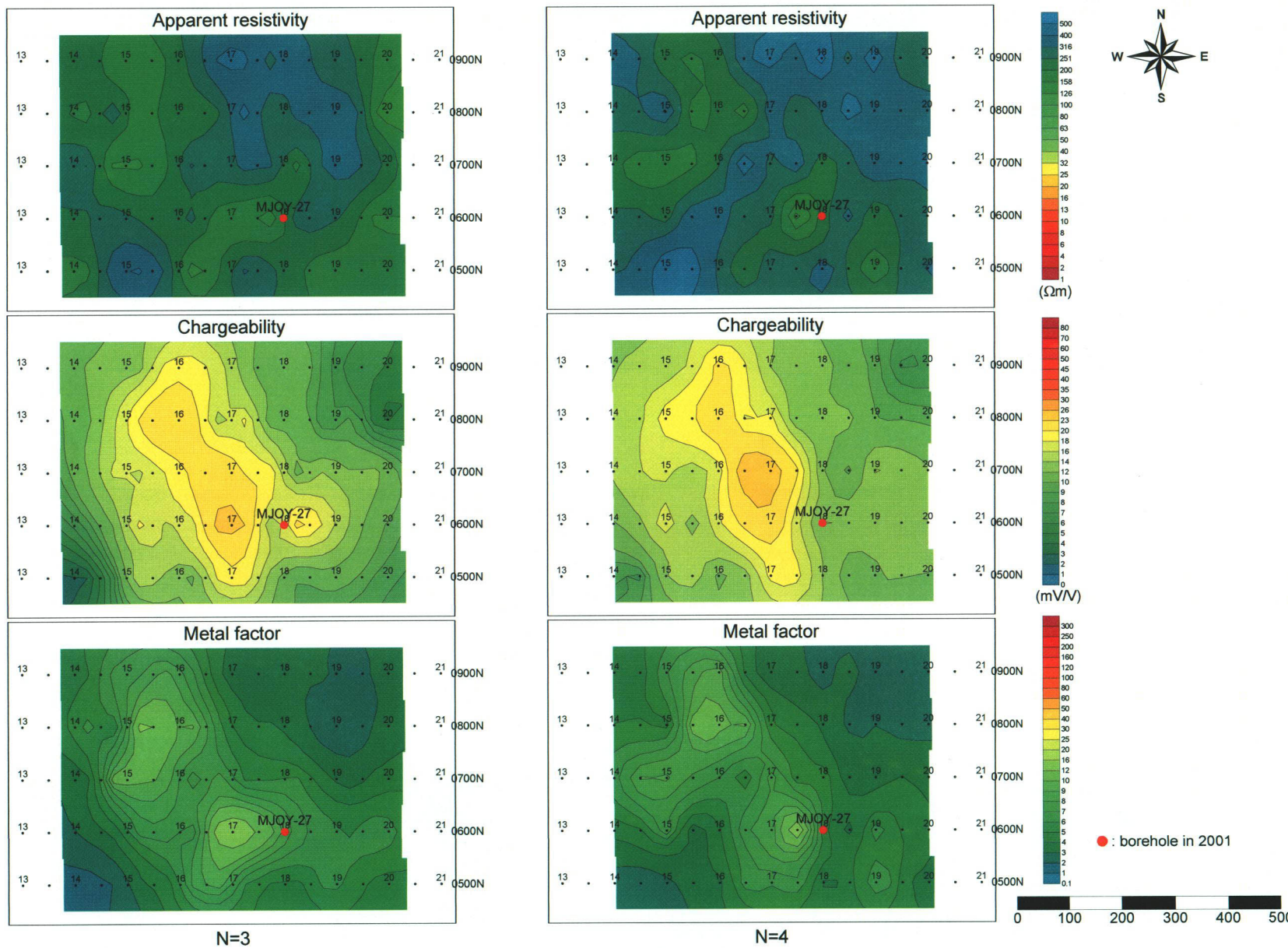
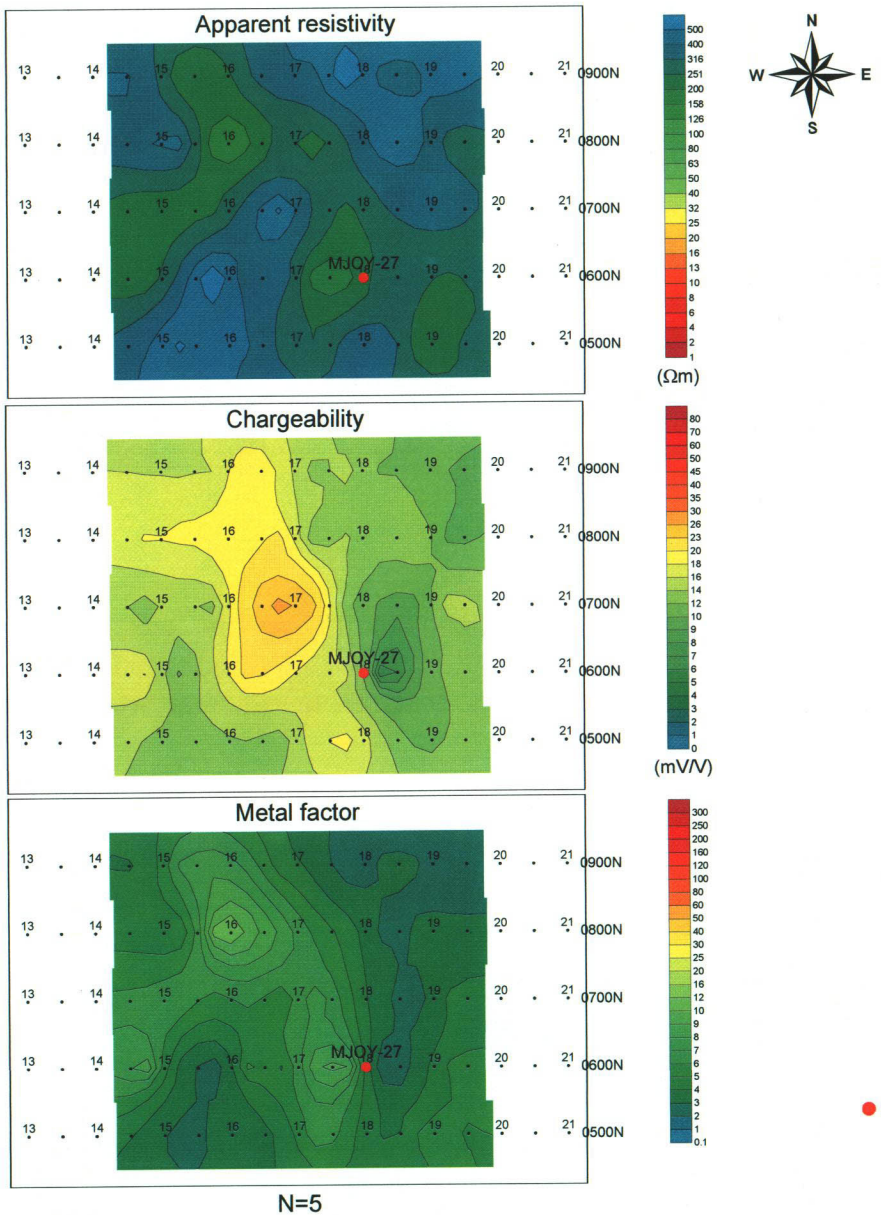


Fig. Ⅱ 2-38(2)　TDIP plane maps for N=3 and 4 in Najaid area



N=5

Fig. Ⅱ 2-38(3)　TDIP plane maps for N=5 in Najaid area